



FQD13N06 / FQU13N06

60V N-Channel MOSFET

General Description

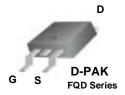
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

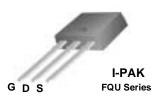
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

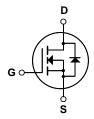
Features

- 10A, 60V, $R_{DS(on)} = 0.14\Omega$ @V_{GS} = 10 V Low gate charge (typical 5.8 nC)
- Low Crss (typical 15 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS Compliant









Absolute Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQD13N06 / FQU13N06	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°C))	10	Α
	- Continuous (T _C = 100°C)		6.3	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	40	Α
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	85	mJ
I _{AR}	Avalanche Current	(Note 1)	10	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3		7.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		28	W
	- Derate above 25°C		0.22	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		4.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

Symbol	Parameter	Test Conditions		Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	60			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 5.0 A		0.11	0.14	Ω
g _{FS}	Forward Transconductance	V _{DS} = 25 V, I _D = 5.0 A (Note 4)		4.9		S
C _{iss}	ic Characteristics Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		240 90	310 120	pF pF
C _{rss}	Reverse Transfer Capacitance	1 = 1.0 WH 12		15	20	pF
	ing Characteristics	1	1			
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_D = 6.5 \text{ A},$		5	20	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		25	60	ns
t _{d(off)}	Turn-Off Delay Time	-		8	25	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		15	40	ns
Q _g	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 13 \text{ A},$		5.8	7.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		2.0		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		2.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				10	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current			40	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 10 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 13 \text{ A,}$		39		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		40		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 990μH, I_{AS} = 10A, V_{DD} = 25V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq 13A, di/dt \leq 300A/us, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

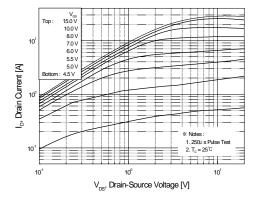


Figure 1. On-Region Characteristics

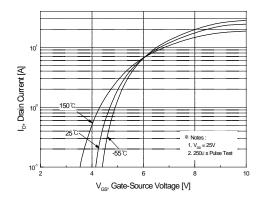


Figure 2. Transfer Characteristics

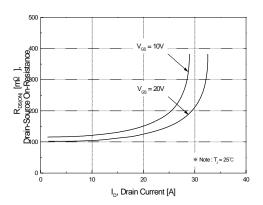


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

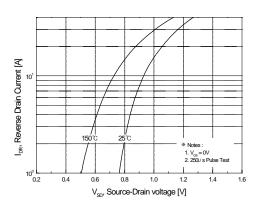


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

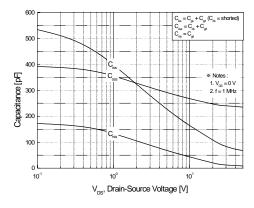


Figure 5. Capacitance Characteristics

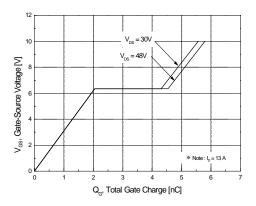
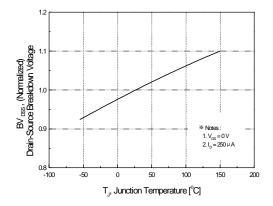


Figure 6. Gate Charge Characteristics

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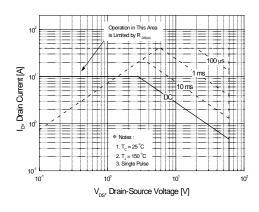
Typical Characteristics (Continued)



2.5 (Notices: 1. V_{cos} = 10.0 (Notices: 1. V_{co}

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



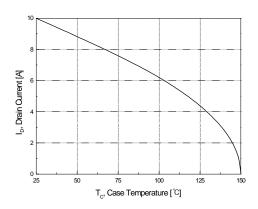


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

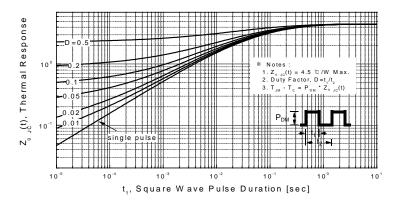
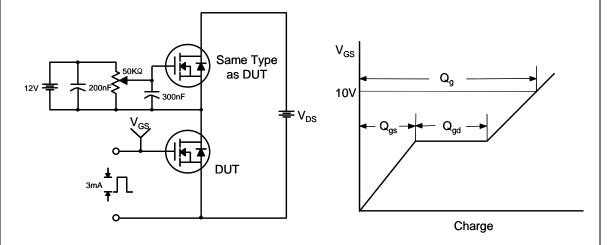


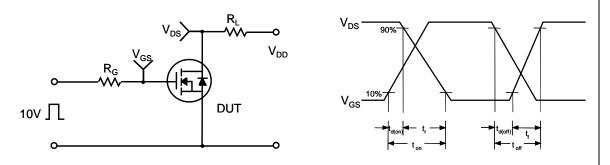
Figure 11. Transient Thermal Response Curve

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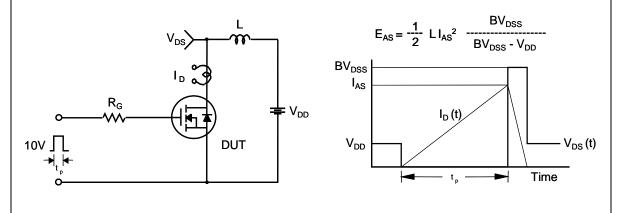
Gate Charge Test Circuit & Waveform



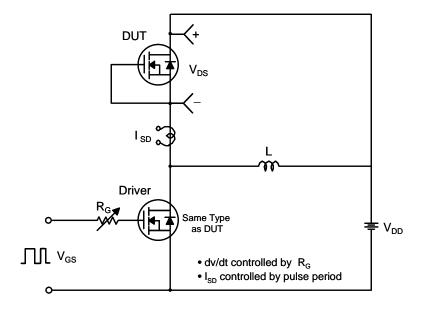
Resistive Switching Test Circuit & Waveforms

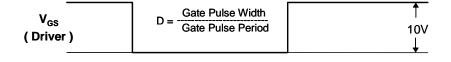


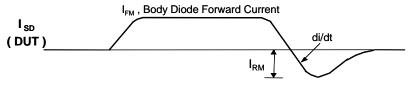
Unclamped Inductive Switching Test Circuit & Waveforms



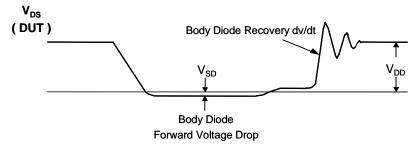
Peak Diode Recovery dv/dt Test Circuit & Waveforms





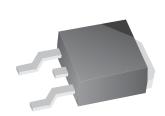


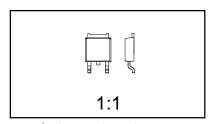
Body Diode Reverse Current



Package Dimensions

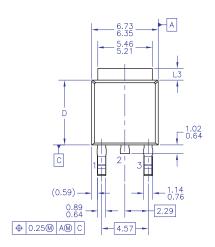
TO-252 (DPAK) (FS PKG Code 36)

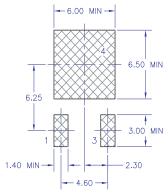




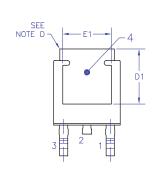
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

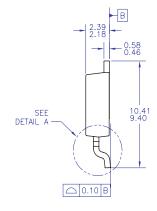
Part Weight per unit (gram): 0.33

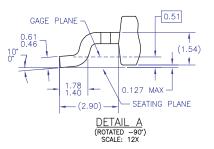




LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

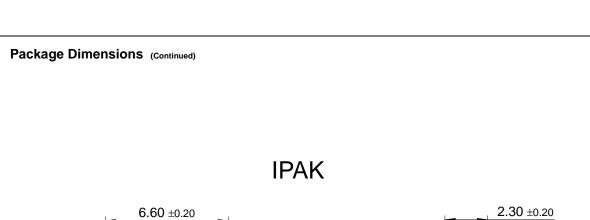
 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

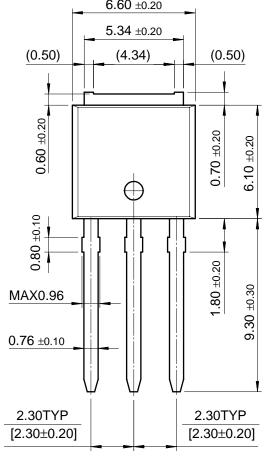
 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

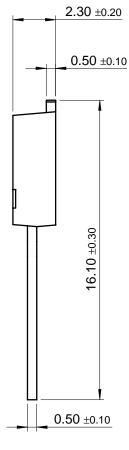
 D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.

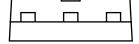
 E) DIMENSIONS L3,D,E1&D1 TABLE:

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4 57 MIN













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Rev. 137